

N-Channel Enhancement-Mode MOSFET**Product Summary**

V_{(BR)DSS} Min (V)	r_{DS(on)} Max (Ω)	V_{GS(th)} (V)	I_D (A)
300	12 @ V _{GS} = 10 V	0.8 to 3	0.18
	20 @ V _{GS} = 4.5 V		

Features

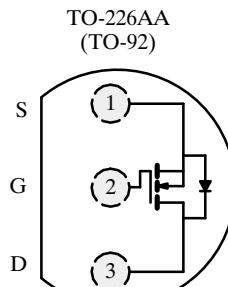
- Low On-Resistance: 9 Ω
- Secondary Breakdown Free: 320 V
- Low Power/Voltage Driven
- Low Input and Output Leakage
- Excellent Thermal Stability

Benefits

- Low Offset Voltage
- Full-Voltage Operation
- Easily Driven Without Buffer
- Low Error Voltage
- No High-Temperature “Run-Away”

Applications

- High-Voltage Drivers: Relays, Solenoids, Lamps, Hammers, Displays, Transistors, etc.
- Telephone Mute Switches, Ringer Circuits
- Power Supply, Converters
- Motor Control



Top View

Absolute Maximum Ratings (T_A = 25°C Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	300	V
Gate-Source Voltage	V _{GS}	± 20	
Continuous Drain Current (T _J = 150°C)	I _D	0.18	A
		0.14	
Pulsed Drain Current	I _{DM}	0.5	W
Power Dissipation	P _D	0.8	
		0.32	
Maximum Junction-to-Ambient	R _{thJA}	156	°C/W
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C

Notes

a. Pulse width limited by maximum junction temperature.

TN3012L

TEMIC

Siliconix

Specifications^a

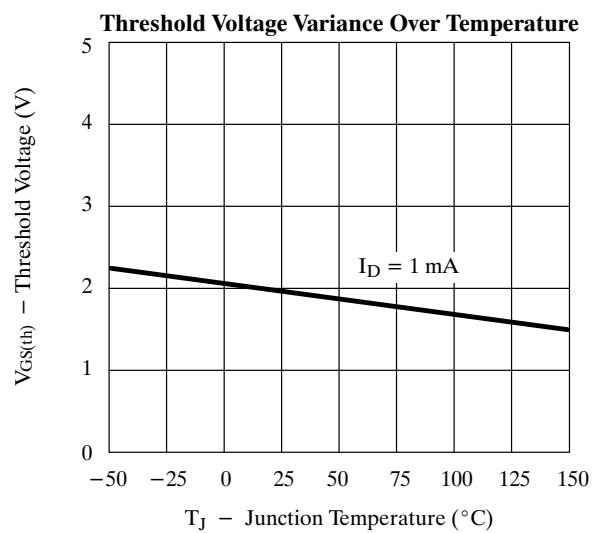
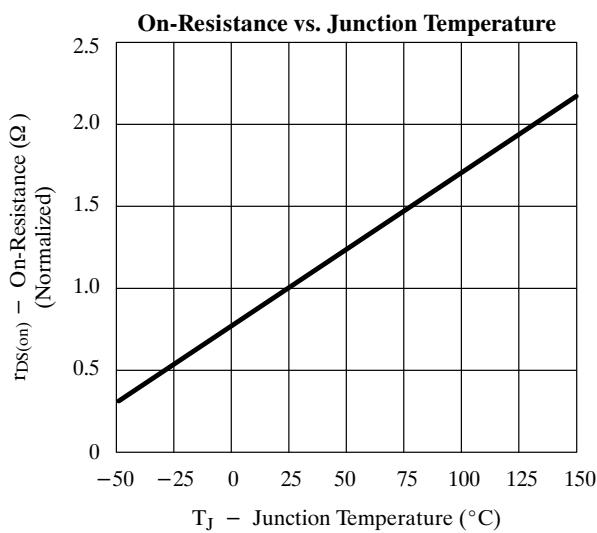
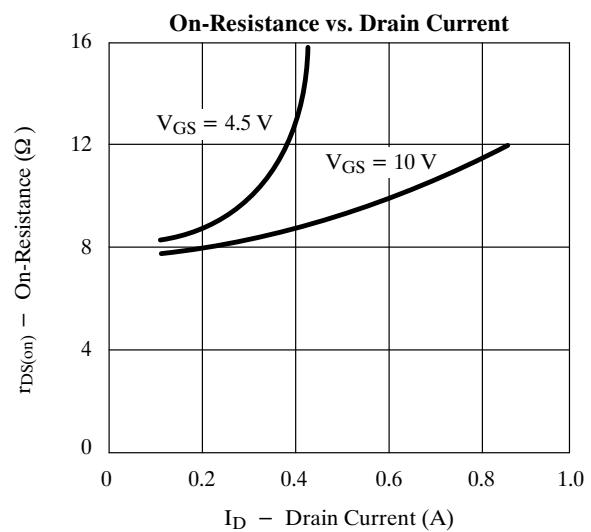
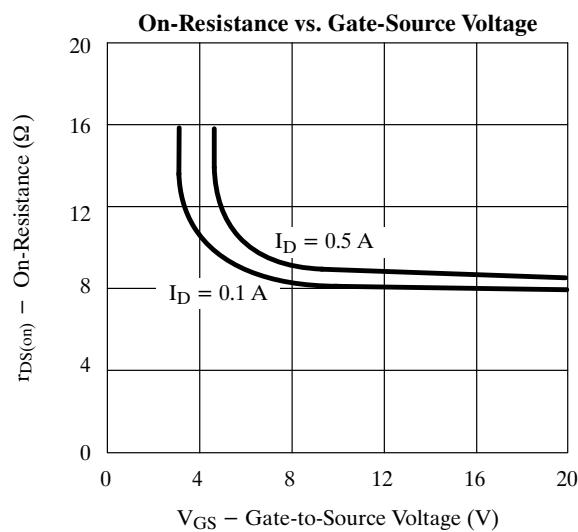
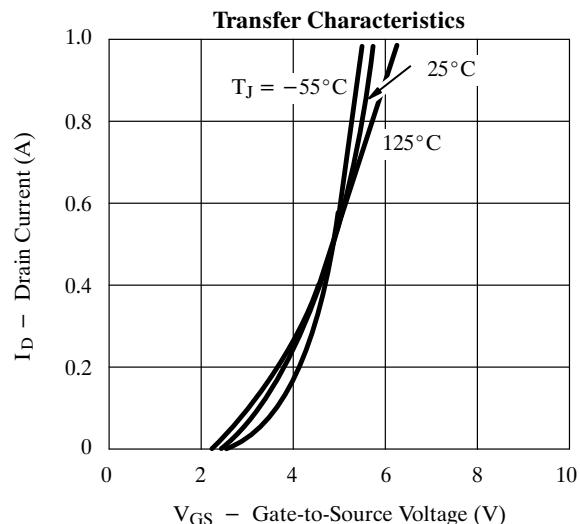
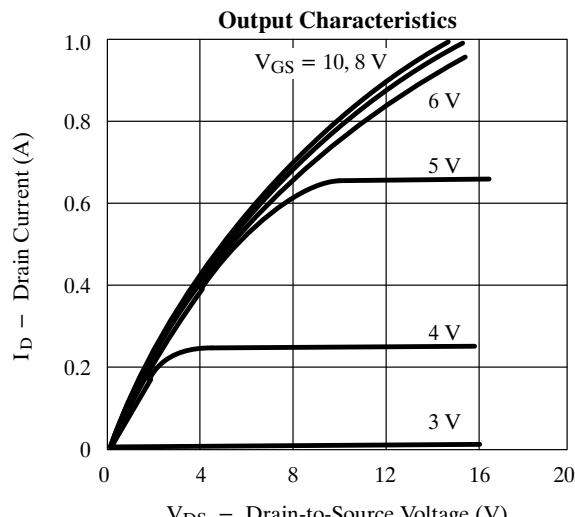
Parameter	Symbol	Test Conditions	Limits			Unit
			Min	Typ ^b	Max	
Static						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 10 µA	300	320		V
Gate-Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 0.25 mA	0.8	2.1	3.0	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 20 V			± 10	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 120 V, V _{GS} = 0 V T _J = 125°C			0.1 5	µA
On-State Drain Current ^c	I _{D(on)}	V _{DS} = 5 V, V _{GS} = 10 V	0.2	0.5		A
Drain-Source On-Resistance ^c	r _{DS(on)}	V _{GS} = 10 V, I _D = 0.18 A		9	12	Ω
		V _{GS} = 4.5 V, I _D = 0.14 A T _J = 125°C		11	20	
				20	40	
Forward Transconductance ^c	g _{fs}	V _{DS} = 15 V, I _D = 0.1 A		160		mS
Diode Forward Voltage	V _{SD}	I _S = 0.18 A, V _{GS} = 0 V		0.8		V
Dynamic						
Total Gate Charge	Q _g	V _{DS} = 50 V, V _{GS} = 10 V, I _D ≈ 100 mA		3300		pC
Gate-Source Charge	Q _{gs}			38		
Gate-Drain Charge	Q _{gd}			1600		
Input Capacitance	C _{iss}	V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz		40		pF
Output Capacitance	C _{oss}			8		
Reverse Transfer Capacitance	C _{rss}			3		
Switching^d						
Turn-On Time	t _{d(on)}	V _{DD} = 50 V, R _L = 500 Ω, I _D ≈ 100 mA V _{GEN} = 10 V, R _G = 25 Ω		5	10	ns
	t _r			20	40	
Turn-Off Time	t _{d(off)}			25	50	
	t _f			30	60	

Notes

- a. T_A = 25°C unless otherwise noted.
- b. For DESIGN AID ONLY, not subject to production testing.
- c. Pulse test: PW ≤ 300 µs duty cycle ≤ 2%.
- d. Switching time is essentially independent of operating temperature.

VNAS30

Typical Characteristics (25°C Unless Otherwise Noted)



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